

Search Notes

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Examiner

Shih-wen Hsieh

Applicant(s)/Patent under
Reexamination

NAKAMURA, SHINICHI

Art Unit

2861

SEARCHED

Class	Subclass	Date	Examiner
347	22,24,29 30,31,32 33	7/27/2006	SWH

INTERFERENCE SEARCHED

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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR

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